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					Examiner Name		740756-2638		
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NAKAYAMA et al., "Microprocess for Fabricating Carbon-Nanombe Probes of a Scanning Probe Microscope" J. Vac. Sci. Technol. B 18/(2), pp. 661-664							e Probes of a 664		
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Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at <u>www.uspto.gov</u> or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 1 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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C	Complete if Known					
Application Number	10/628,239					
Filing Date	July 29, 2003					
First Named Inventor	Koji MORIYA et al.					
Art Unit	2818					
Examiner Name	Dung Anh Le					
Attorney Docket Number	740756-2638					

			U.S. PATENT DOC	JMENT	rs					
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		R. MARTEL et al.; "Single and Multi-Well Carbon Nanotube Field-Effect Transistors"; Appl. Phys. Lett., 10/26/1998, Vol. 73, No. 17; pp. 2447-2449.								
		K. LIU et al.; "Conductance Spikes in Single-Walled Carbon Nanotube Field-Effect"; Appl. Phys. Lett., 10/18/1999; Vol. 75, No. 16; pp. 2494-2496.								
		T. YAMADA; "Analysis of Submicron Carbon Nanotube Field-Effect Transistors"; Appl. Phys. Lett., 01/31/2000; Vol. 76, No. 5; pp. 628-630.								
		A. BACHTOLD et al.; "Contacting Carbon Nanotubes Selectively with Low-Ohmic Contacts for Four-Probe Electric Measurements"; Appl. Phys. Lett., 07/13/1998; Vol. 73, No. 2, pp. 274-276.								
		S. FRANK et al.; "Carbon Nanotube Quantum Resistors"; Science, 06/12/1998; Vol. 280, pp. 1744-1746.								
		M. BOCKRATH et al.; "Single-Electron Transport in Ropes of Carbon Nanotubes"; Science, 03/28/1997, Vol. 275, pp. 1922-1925.								
		"Carbon Nanotube – Progressing Material Development Technique and Development of Application – (with a partial translation)"; 04/26/2002; pp. 157-158.								
Examiner Signature				Date	12	12005				

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